

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/875,138	MIYAKE ET AL.	
Examiner	Art Unit	
Nhan T. Tran	2615	

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
UPDATED EAST SEARCH (USPAT, PGPUB, JPO, EPO, DERWENT)	8/20/2005	NT		
(INCLUDING SEARCH ST UPDATED EAST SEARCH (USPAT, PGPUB, JPO, EPO, DERWENT) TUAN HO 348/42,459,49 (text search -see search history printout) 348/\$.; 358/\$.; 250/208.1; 396/\$. (text search - see serach history	8/19/2005	NT		
348/42,459,49 (text search -see search history printout)	8/20/2005	NT		
348/\$.; 358/\$.; 250/208.1; 396/\$. (text search - see serach history printout)	8/20/2005	NT		